

# PATENT ABSTRACTS OF JAPAN

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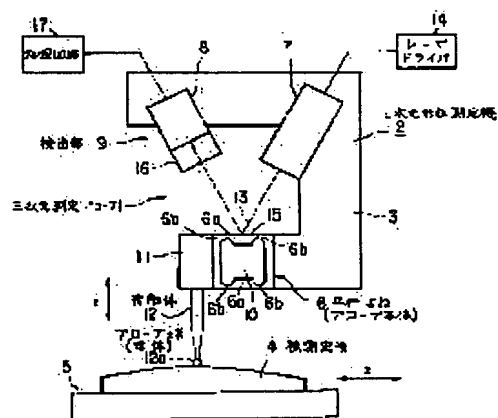
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## (54) THREE-DIMENSIONAL MEASURING PROBE

### (57)Abstract:

**PURPOSE:** To provide a three-dimensional measuring probe with a high measuring accuracy without damaging an object.

**CONSTITUTION:** This apparatus includes a parallel spring 6 deformable elastically, a contact body 12 which is mounted on the parallel spring 6 and moves having a probe ball 12a at the tip thereof while keeping the probe ball 12a in contact with an object 4 to deform the parallel spring 6 elastically according to irregularities of the surface of the object 4 and a detecting section 9 to detect a deformation value of the parallel spring 6 in an optical lever manner.



## LEGAL STATUS

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